

*Geochim. Cosmochim. Acta* **53** (1988) p. 1235.  
 17. M.F. Hochella Jr., in *Reviews in Mineralogy #23: Mineral-Water Interface Geochemistry*, edited by M.F. Hochella and A.F. White (Mineralogical Society of America, Washington, DC, 1990) p. 87.  
 18. G.E. Brown, in *Reviews in Mineralogy #23: Mineral-Water Interface Geochemistry*, edited by M.F. Hochella and A.F. White (Mineralogical Society of America, Washington, DC, 1990) p. 309.  
 19. K.F. Hayes, A.L. Roe, G.E. Brown, K.O. Hodgson, J.O. Leckie, and G.A. Parks, *Science* **238** (1987) p. 783.  
 20. C.M. Eggleston, M.F. Hochella Jr., and G.A. Parks (1990) Geological Society of America Abst. with Programs, A292.  
 21. P.A. Johnsson, C.M. Eggleston, and M.F. Hochella Jr., *American Mineral.* **76** (1991) p. 1443.  
 22. A.J. Gratz, S. Manne, and P.K. Hansma, *Science* **251** (1991) p. 1343.  
 23. P.E. Hillner, A.J. Gratz, S. Manne, and P.K. Hansma, *Geology* (1992) (submitted).  
 24. M.F. Hochella Jr., C.M. Eggleston, V.B. Elings, and M. Thompson, *American Mineral.*

*75* (1990) p. 723.  
 25. H. Hartman, G. Sposito, A. Yang, S. Manne, S.A.C. Gould, and P.K. Hansma, *Clays Clay Minerals* **38** (1990) p. 337.  
 26. H. Lindgreen, J. Garnaes, P.L. Hansen, F. Besenbacher, E. Laegsgaard, I. Stensgaard, S.A. Gould, and P.K. Hansma, *American Mineral.* **76** (1991) p. 1218.

27. A.L. Weisenhorn, J.E. MacDougall, S.A. Gould, S.D. Cox, W.S. Wise, J. Massie, P. Maivald, V.B. Elings, G.D. Stucky, and P.K. Hansma, *Science* **247** (1990) p. 1330.  
 28. C.M. Eggleston, and M.F. Hochella Jr., *Geochim. Cosmochim. Acta* **54** (1990) p. 1511.  
 29. C.M. Eggleston, and M.F. Hochella Jr., *Science* **254** (1991) p. 983. □

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